# National Semiconductor

# ADC0841 8-Bit µP Compatible A/D Converter

## **General Description**

The ADC0841 is a CMOS 8-bit successive approximation A/D converter. Differential inputs provide low frequency input common mode rejection and allow offsetting the analog range of the converter. In addition, the reference input can be adjusted enabling the conversion of reduced analog ranges with 8-bit resolution.

The A/D is designed to operate with the control bus of a variety of microprocessors. TRI-STATE® output latches that directly drive the data bus permit the A/D to be configured as a memory location or I/O device to the microprocessor with no interface logic necessary.

### Features

- Easy interface to all microprocessors
- Operates ratiometrically or with 5 V<sub>DC</sub>
- voltage reference
- No zero or full-scale adjust required
- Internal clock
- OV to 5V input range with single 5V power supply
- 0.3" standard width 20-pin package
- 20 Pin Molded Chip Carrier Package

### **Key Specifications**

- Resolution 8 Bits
- Total Unadjusted Error ± 1/2 LSB and ± 1 LSB
- Single Supply 5 V<sub>DC</sub>
  - Low Power
     15 mW

     Conversion Time
     40 μs
- \_\_\_\_\_



### Absolute Maximum Ratings (Notes 1 & 2)

If Military/Aerospace specified devices are required, please contact the National Semiconductor Sales Office/Distributors for availability and specifications.

Supply Voltage (V <sub>CC</sub> )	6.5V
Voltage Logic Control Inputs	-0.3V to V <sub>CC</sub> $+0.3V$
At Other Inputs and Outputs	-0.3V to V <sub>CC</sub> + 0.3V
Input Current Per Pin (Note 3)	± 5 mA
Input Current Per Package (Note 3)	±20 mA
Storage Temperature	-65°C to +150°C
Package Dissipation at T <sub>A</sub> = 25°C	875 mW

Lead Temp. (Soldering, 10 seconds)	
Dual-In-Line Package (Plastic)	260°C
Dual-In-Line Package (Ceramic)	300°C
Molded Chip Carrier Package	
Vapor Phase (60 seconds)	215°C
Infrared (15 seconds)	220°C
ESD Susceptibility (Note 10)	800V

## Operating Conditions (Notes 1 and 2)

Supply Voltage (V <sub>CC</sub> )	4.5 V <sub>DC</sub> to 6.0 V <sub>DC</sub>
Temperature Range	T <sub>MIN</sub> ≤T <sub>A</sub> ≤T <sub>MAX</sub>
ADC0841BCN, ADC0841CCN	0°C≤T <sub>A</sub> ≤70°C
ADC0841BCJ, ADC0841CCJ,	−40°C≤T <sub>A</sub> ≤85°C
ADC0841BCV, ADC0841CCV	
ADC0841BJ, ADC0841CJ	−55°C≤T <sub>A</sub> ≤125°C

**Electrical Characteristics** The following specifications apply for  $V_{CC} = 5 V_{DC}$  unless otherwise specified. Boldface limits apply from T<sub>MIN</sub> to T<sub>MAX</sub>; all other limits  $T_A = T_i = 25^{\circ}C$ .

		ADC0841BJ, ADC0841BCJ ADC0841CJ, ADC0841CCJ			ADC0841BCN, ADC0841CCN ADC0841BCV, ADC0841CCV				
Parameter	Conditions	Typ (Note 6)	Tested Limit (Note 7)	Design Limit (Note 8)	Typ (Note 6)	Tested Limit (Note 7)	Design Limit (Note 8)	Units	
CONVERTER AND MULTIPLEXER CHARACTERISTICS									
Maximum Total Unadjusted Error ADC0841BCN, BCV ADC0841BJ, BCJ ADC0841CCN, CCV ADC0841CJ, CCJ	V <sub>REF</sub> = 5.00 V <sub>DC</sub> (Note 4)		± ½ ± 1			± 1⁄2 ± 1	± ½ ± 1	LSB LSB LSB LSB	
Minimum Reference Input Resistance		2.4	1.1		2.4	1.2	1.1	kΩ	
Maximum Reference Input Resistance		2.4	5.9		2.4	5.4	5.9	kΩ	
Maximum Common-Mode Input Voltage	(Note 5)		V <sub>CC</sub> +0.05			V <sub>CC</sub> +0.05	V <sub>CC</sub> +0.05	v	
Minimum Common-Mode Input Voltage	(Note 5)		GND-0.05			GND-0.05	GND-0.05	V	
DC Common-Mode Error	Differential Mode	± 1⁄16	± 1/4		± 1/16	± 1/4	± 1/4	LSB	
Power Supply Sensitivity	$V_{CC} = 5V \pm 5\%$	± 1/16	± 1/8		± 1/16	± 1/8	± 1/8	LSB	

ADC0841

**Electrical Characteristics** The following specifications apply for  $V_{CC} = 5 V_{DC}$  unless otherwise specified. Boldface limits apply from T<sub>MIN</sub> to T<sub>MAX</sub>; all other limits  $T_A = T_j = 25^{\circ}C$ . (Continued)

		×	ADC0841BJ, ADC0841BCJ ADC0841CJ, ADC0841CCJ			ADC0841BCN, ADC0841CCN ADC0841BCV, ADC0841CCV			
Symbol	Parameter	Conditions	Typ (Note 6)	Tested Limit (Note 7)	Design Limit (Note 8)	Typ (Note 6)	Tested Limit (Note 7)	Design Limit (Note 8)	Units
DIGITAL A	ND DC CHARACTERIS	TICS							
V <sub>IN(1)</sub>	Logical "1" Input Voltage (Min)	V <sub>CC</sub> =5.25V		2.0			2.0	2.0	v
V <sub>IN(0)</sub>	Logical "0" Input Voltage (Max)	V <sub>CC</sub> =4.75V		0.8			0.8	0.8	v
l <sub>IN(1)</sub>	Logical "1" Input Current (Max)	V <sub>IN</sub> =5.0V	0.005	1		0.005		1	μΑ
I <sub>IN(0)</sub>	Logical "0" Input Current (Max)	V <sub>IN</sub> =0V	-0.005	-1		-0.005		-1	μΑ
V <sub>OUT(1)</sub>	Logical "1" Output Voltage (Min)	V <sub>CC</sub> =4.75V I <sub>OUT</sub> =-360 μA I <sub>OUT</sub> =-10 μA		2.4 4.5			2.8 4.6	2.4 4.5	v v
V <sub>OUT(0)</sub>	Logical "0" Output Voltage (Max)	V <sub>CC</sub> =4.75V I <sub>OUT</sub> =1.6 mA		0.4			0.34	0.4	V
lout	TRI-STATE Output Current (Max)	V <sub>OUT</sub> =0V V <sub>OUT</sub> =5V	-0.01 0.01	- 3 3		-0.01 0.01	-0.3 0.3	-3 3	μΑ μΑ
ISOURCE	Output Source Current (Min)	V <sub>OUT</sub> =0V	-14	-6.5		-14	-7.5	-6.5	mA
ISINK	Output Sink Current (Min)	V <sub>OUT</sub> =V <sub>CC</sub>	16	8.0		16	9.0	8.0	mA
Icc	Supply Current (Max)	CS = 1, V <sub>REF</sub> Open	1	2.5		1	2.3	2.5	mA

**AC Characteristics** The following specifications apply for  $V_{CC} = 5V_{DC}$ ,  $t_r = t_f = 10$  ns unless otherwise specified. Boldface limits apply from  $T_{MIN}$  to  $T_{MAX}$ ; all other limits  $T_A = T_J = 25^{\circ}C$ .

Symbol	Parameter	Conditions	Typ (Note 6)	Tested Limit (Note 7)	Design Limit (Note 8)	Units
tc	Maximum Conversion Time (See Graph)		30	40	60	μs
tw(WR)	Minimum WR Pulse Width	(Note 9)	50	150		ns
tACC	Maximum Access Time (Delay from Falling Edge of RD to Output Data Valid)	C <sub>L</sub> = 100 pF (Note 9)	145	225		ns
t <sub>1H</sub> , t <sub>0H</sub>	TRI-STATE Control (Maximum Delay from Rising Edge of RD to Hi-Z State)	$C_{L} = 10 \text{ pF}, R_{L} = 10 \text{ k},$ $t_{r} = 20 \text{ ns} (\text{Note 9})$	125		200	ns
t <sub>WI</sub> , t <sub>RI</sub>	Maximum Delay from Falling Edge of WR or RD to Reset of INTR	(Note 9)	200	400		ns
C <sub>IN</sub>	Capacitance of Logic Inputs		5			pF
COUT	Capacitance of Logic Outputs		5			рF

Note 1: Absolute Maximum Ratings indicate limits beyond which damage to the device may occur. DC and AC electrical specifications do not apply when operating the device beyond its specified operating conditions.

Note 2: All voltages are measured with respect to the ground pins.

Note 3: During over-voltage conditions ( $V_{IN}$  < 0V and  $V_{IN}$  >  $V_{CC}$ ) the maximum input current at any one pin is ±5 mA. If the current is limited to ±5 mA at all the pins no more than four pins can be in this condition in order to meet the Input Current Per Package (±20 mA) specification.

Note 4: Total undajusted error includes offset, full-scale, and linearity.

Note 5: For  $V_{IN}(-) \ge V_{IN}(+)$  the digital output code will be 0000 0000. Two on-chip diodes are tied to each analog input, which will forward-conduct for analog input voltages one diode drop below ground or one diode drop greater than  $V_{CC}$  supply. Be careful during testing at low  $V_{CC}$  levels (4.5V), as high level analog inputs (5V) can cause this input diode to conduct, especially at elevated temperatures, and cause errors for analog inputs near full-scale. The spec allows 50 mV forward bias of either diode. This means that as long as the analog  $V_{IN}$  does not exceed the supply voltage by more than 50 mV, the output code will be correct. To achieve an absolute 0  $V_{DC}$  to 5  $V_{DC}$  input voltage range will therefore require a minimum supply voltage of 4.950  $V_{DC}$  over temperature variations, initial tolerance and loading.

Note 6: Typicals are at 25°C and represent most likely parametric norm.

Note 7: Tested limits are guaranteed to National's AOQL (Average Outgoing Quality Level).

Note 8: Design limits are guaranteed but not 100% production tested. These limits are not used to calculate outgoing quality levels.

Note 9: The temperature coefficient is 0.3%/°C.

Note 10: Human body model, 100 pF discharged through 1.5 k $\Omega$  resistor.

## **Timing Diagram**



TL/H/8557-9

Note 1: Read strobe must occur at least 600 ns after the assertion of interrupt to guarantee reset of INTR.

# Typical Performance Characteristics



ADC0841



### **Functional Description**

A conversion is initiated via the  $\overline{\text{CS}}$  and  $\overline{\text{WR}}$  lines. If the data from a previous conversion is not read, the  $\overline{\text{INTR}}$  line will be low. The falling edge of  $\overline{\text{WR}}$  will reset the  $\overline{\text{INTR}}$  line high and ready the A/D for a conversion cycle. The rising edge of  $\overline{\text{WR}}$  starts a conversion. After the conversion cycle ( $t_C \leq 60$   $\mu$ sec), which is set by the internal clock frequency, the digital data is transferred to the output latch and the  $\overline{\text{INTR}}$  is asserted low. Taking  $\overline{\text{CS}}$  and  $\overline{\text{RD}}$  low resets  $\overline{\text{INTR}}$  output high and transfers the conversion result on the output data lines (DB0–DB7).

# **Applications Information**

#### **1.0 REFERENCE CONSIDERATIONS**

The voltage applied to the reference input of this converter defines the voltage span of the analog input (the difference between V<sub>IN(MAX)</sub> and V<sub>IN(MIN)</sub>) over which the 256 possible output codes apply. The device can be used in either ratiometric applications or in systems requiring absolute accuracy. The reference pin must be connected to a voltage source capable of driving the minimum reference input resistance of 1.1 k $\Omega$ . This pin is the top of a resistor divider string used for the successive approximation conversion.

In a ratiometric system (*Figure 1a*), the analog input voltage is proportional to the voltage used for the A/D reference. This voltage is typically the system power supply, so the  $V_{REF}$  pin can be tied to  $V_{CC}$ . This technique relaxes the stability requirements of the system reference as the analog input and A/D reference move together maintaining the same output code for a given input condition.

For absolute accuracy (*Figure 1b*), where the analog input varies between very specific voltage limits, the reference pin can be biased with a time and temperature stable voltage source. The LM385 and LM336 reference diodes are good low current devices to use with this converter.

The maximum value of the reference is limited to the V<sub>CC</sub> supply voltage. The minimum value, however, can be quite small (see Typical Performance Characteristics) to allow direct conversions of transducer outputs providing less than a 5V output span. Particular care must be taken with regard to noise pickup, circuit layout and system error voltage sources when operating with a reduced span due to the increased sensitivity of the converter (1 LSB equals  $V_{\text{REF}}/256$ ).

#### 2.0 THE ANALOG INPUTS

#### 2.1 Analog Differential Voltage Inputs and Common-Mode Rejection

The differential inputs of this converter actually reduce the effects of common-mode input noise, a signal common to both selected "+" and "-" inputs for a conversion (60 Hz is most typical). The time interval between sampling the "+" input and then the "-" input is  $\frac{1}{2}$  of a clock period. The change in the common-mode voltage during this short time interval can cause conversion errors. For a sinusoidal common-mode signal this error is:

$$V_{\text{ERROR(MAX)}} = V_{\text{peak}} (2\pi f_{\text{CM}}) \times 0.5 \times \left(\frac{t_{\text{C}}}{8}\right)$$

where  $f_{CM}$  is the frequency of the common-mode signal, Vpeak is its peak voltage value and  $t_{C}$  is the conversion time.

For a 60 Hz common-mode signal to generate a 1/4 LSB error ( $\approx 5$  mV) with the converter running at 40  $\mu$ S, its peak value would have to be 5.43V. This large a common-mode signal is much greater than that generally found in a well designed data acquisition system.

#### 2.2 Input Current

Due to the sampling nature of the analog inputs, short duration spikes of current enter the "+" input and exit the "-" input at the clock edges during the actual conversion. These currents decay rapidly and do not cause errors as the internal comparator is strobed at the end of a clock period. Bypass capacitors at the inputs will average these currents and cause an effective DC current to flow through the output resistance of the analog signal source. Bypass capacitors should not be used if the source resistance is greater than 1 k $\Omega$ . An op amp RC active low pass filter can provide both impedance buffering and noise filtering should a high impedance signal source be required.

#### 3.0 OPTIONAL ADJUSTMENTS

#### 3.1 Zero Error

The zero of the A/D does not require adjustment. If the minimum analog input voltage value, V<sub>IN(MIN)</sub>, is not ground, a zero offset can be done. The converter can be made to output 0000 0000 digital code for this minimum Input voltage by biasing the V<sub>IN</sub> (-) input at this V<sub>IN(MIN)</sub> value.

The zero error of the A/D converter relates to the location of the first riser of the transfer function and can be measured by grounding the V<sup>-</sup> input and applying a small magnitude positive voltage to the V<sup>+</sup> input. Zero error is the difference between actual DC input voltage which is necessary to just cause an output digital code transition from 0000 0000 00001 and the ideal  $\frac{1}{2}$  LSB value ( $\frac{1}{2}$  LSB = 9.8 mV for V<sub>REF</sub> = 5.000 V<sub>DC</sub>).

#### 3.2 Full-Scale

The full-scale adjustment can be made by applying a differential input voltage which is 1  $\frac{1}{2}$  LSB down from the desired analog full-scale voltage range and then adjusting the magnitude of the V<sub>REF</sub> input for a digital output code changing from 1111 1110 to 1111 1111.

# 3.3 Adjusting for an Arbitrary Analog Input Voltage Range

If the analog zero voltage of the A/D is shifted away from ground (for example, to accommodate an analog input signal which does not go to ground), this new zero reference should be properly adjusted first. A voltage which equals this desired zero reference plus  $\frac{1}{2}$  LSB (where the LSB is calculated for the desired analog span, 1 LSB = analog span/256) is applied to the "+" input (V<sub>IN</sub>(<sup>+</sup>)) and the zero reference voltage at the "-" input (V<sub>IN</sub>(<sup>-</sup>))should then be adjusted to just obtain the 00<sub>HEX</sub> to 01<sub>HEX</sub> code transition.

#### Applications Information (Continued) 5٧ 5٧ o Q V<sub>CC</sub> TRANSDUCER V<sub>cc</sub> 2.7 kΩ OV TO 1.25V V<sub>REF</sub> VRFF $V_{IN}(+)$ V<sub>IN</sub>(+) 1.25V ADC0841 ADC0841 LM385 $V_{IN}(-)$ $V_{IN}(-)$ AGND AGND TL/H/8557-11 TL/H/8557-12 a) Ratiometric b) Absolute with a Reduced Span



Zero-Shift and Span Adjust (2V  $\leq$  V  $_{IN}$   $\leq$  5V)  $$v_{0C}$ $v_{0C}$ $v$ 

Vcc

VREF

10

FS.

AD.

1/2 LM358

1 µF

SETS

LM336-2.5

VOLTAGE SPAN

VIN(+)

V<sub>IN</sub>(-)

ADC0841

330

The full-scale adjustment should be made [with the proper  $V_{IN}$  (-) voltage applied] by forcing a voltage to the  $V_{IN}(+)$  input which is given by:

$$V_{IN}$$
 (+) fs adj =  $V_{MAX} - 1.5 \left[ \frac{(V_{MAX} - V_{MIN})}{256} \right]$ 

where  $V_{MAX}$  = the high end of the analog input range and

SETS ZERO CODE VOLTAGE

2.7k

(2V

2 V<sub>DC</sub> ZERO ADJ  $V_{MIN}$  = the low end (the offset zero) of the analog range. (Both are ground referenced.)

ADC0841

The V<sub>REF</sub> (or V<sub>CC</sub>) voltage is then adjusted to provide a code change from  $\mathsf{FE}_{\text{HEX}}$  to  $\mathsf{FF}_{\text{HEX}}$ . This completes the adjustment procedure.

For an example see the Zero-Shift and Span Adjust circuit below.

1.2k

TL/H/8557-13



## Applications Information (Continued)





TL/H/8557-19





3-167

ADC0841

# Applications Information (Continued)

#### SAMPLE PROGRAM FOR ADC0841—INS8039 INTERFACE CONVERTING TWO RATIOMETRIC, DIFFERENTIAL SIGNALS

			ORG	0H	
0000	04 10		JMP	BEGIN	;START PROGRAM AT ADDR 10
			ORG	10H	;MAIN PROGRAM
0010	B9 FF	BEGIN:	MOV	R1,#0FFH	LOAD R1 WITH A UNUSED ADDR
					;LOCATION
0012	B8 20		MOV	R0,#20H	;A/D DATA ADDRESS
0014	89 FF	1.1	ORL	P1,#0FFH	SET PORT 1 OUTPUTS HIGH
0016	23 00		MOV	A,00H	;LOAD THE ACC WITH 00
0018	14 50	· · · · ·	CALL	CONV	;CALL THE CONVERSION SUBROUTINE
			;CONTINU	E MAIN PROGRAM	Λ
		<i>1</i> 2	;CONVER	SION SUBROUTIN	E
			ENTRY:A	CC—A/D MUX DA	TA
			;EXIT: ACC	CONVERTED D	ATA
			ORG	50H	
0050	99 FE	CONV:	ANL	P1,#0FEH	;CHIP SELECT THE A/D
0052	91		MOVX	@R1,A	START CONVERSION
0053	09	LOOP:	IN	, A,P1	;INPUT INTR STATE
0054	32 53		JB1	LOOP	; IF $\overline{INTR} = 1$ GOTO LOOP
0056	81		MOVX	A,@R1	; IF $\overline{INTR} = 0$ INPUT A/D DATA
0057	89 01		ORL	P1,&01H	;CLEAR THE A/D CHIP SELECT
0059	A0		MOV	@R0,A	;STORE THE A/D DATA
005A	83		RET		;RETURN TO MAIN PROGRAM





TL/H/8557-20

### Applications Information (Continued)



TL/H/8557-21

#### SAMPLE PROGRAM FOR ADC0841—NSC800 INTERFACE

0010		NCONV	EQU	16	;TWICE THE NUMBER OF REQUIRED ;CONVERSIONS
000F		DEL	EQU	15	DELAY 60 µsec CONVERSION
001F		CS	EQU	1FH	THE BOARD ADDRESS
3C00		ADDTA	EQU	003CH	;START OF RAM FOR A/D :DATA
0000'	00	DTA:	DB	08H	: DATA
0001'	0E 1F	START:	LD	C.CS	, BAIN
0003'	06 16	01/411	LD	B,NCONV	
0005'	21 0000'		LD	HL,DTA	
0008'	11 003C		LD	DE,ADDTA	
000B'	ED A3	STCONV:	OUTI	02,00010	START A CONVERSION
000D'	EB	0100111	EX	DE.HL	HL = RAM ADDRESS FOR THE
0002	20		EX	52,112	;A/D DATA
000E'	3E 0F		LD	A,DEL	,
0010'	3D	WAIT:	DEC	A	;WAIT 60 μsec FOR THE
0011'	C2 0013'		JP	NZ,WAIT	CONVERSION TO FINISH
0014'	ED A2		INI		STORE THE A/D'S DATA
					THE REQUIRED CONVERSIONS COMPLETED?
0016′	EB		EX	DE,HL	
0017'	C2 000E'		JP	NZ,STCONV	IF NOT GOTO STCONV
					-

END

Note: A conversion is started, then a 60  $\mu$ s wait for the A/D to complete a conversion and the data is stored at address ADDTA for the first conversion, ADDTA + 1 for the second conversion, etc. for a total of 8 conversions.

# **Ordering Information**

Temperature	Total Unad	justed Error	Package	
Range	±1/2 LSB	±1 LSB	Outline	
0°C to +70°C	ADC0841BCN	ADC0841CCN	N20A Molded Dip	
-40°C to +85°C	ADC0841BCJ	ADC0841CCJ	J20A Cerdip	
	ADC0841BCV	ADC0841CCV	V20A Molded Chip Carrier	
-55°C to +125°C	ADC0841BJ	ADC0841CJ	J20A Cerdip	